It is my great pleasure to welcome you to the 2000 IEEE International Workshop on Memory Technology, Design and Testing. This is the 8th year of this exciting event. Since the inception in 1993, this workshop has maintained its key attributes of high quality technical sessions, informal discussions, keynote by a senior executive, detailed technical tutorial presentation on the hottest technology. It is my greatest pleasure to report that we are continuing with our tradition in every aspect this year.

Under the leadership of Tom Wik, the technical program committee has put together a 2-day program that contains 17 papers, two detailed technical tutorials and a panel session discussing future memory challenges. In addition, Dr. Handel Jones, the President of IBS Inc. will deliver the keynote addressing the key trends and impacts of memory technology and design.

A large number of internationally renowned experts on process, design and test have participated in the program committee. I am very thankful to all program committee members for their work, help and support. The continued support from TTTC, the Computer Society, the Solid State Circuits Society and the IEEE has been invaluable for the success of this Workshop. On behalf of the entire program committee, I thank all authors who submitted their work. The most important contribution to the workshop is by the participants who bring a broad range of expertise and enrich everyone’s learning experience. I thank all the participants who made this Workshop successful.

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